EXERCISES 551

		E		$\overline{+}$		$^{+}$
		D			$^{+}$	$^{+}$
А	B	$\, C \,$				
		0	37.29	57.81	42.87	47.07
$^{+}$		0	4.35	24.89	8.23	14.69
	$^{+}$	0	9.51	13.21	10.10	11.19
$^{+}$	$^{+}$	0	9.15	13.39	10.30	11.23
	0		20.24	27.71	22.28	24.32
$^{+}$	0		4.48	11.40	5.44	8.23
	0	$+$	18.40	30.65	20.24	24.45
$^+$	0	$^{+}$	2.29	14.94	4.30	8.49
$\overline{0}$			22.42	42.68	21.64	30.30
0	$^{+}$		10.08	13.56	9.85	11.38
0		$^{+}$	13.19	50.60	18.84	30.97
$\overline{0}$	$^{+}$	$^{+}$	7.44	15.21	9.78	11.82
0	0	0	12.29	19.62	13.14	14.54
θ	0	0	11.49	20.60	12.06	13.49
0	0	0	12.20	20.15	14.06	13.38

Table 12.20 Product Array Design for Chemical Process Experiment

- 4. Because the elastometric connector experiments described in Section 12.3 required physical experimentation, Song and Lawson (1988) suggested using a single array design to save on the number of experiments required. Table 12.21 shows a resolution IV 2^{7-2} fractional factorial design and the resulting pull-off force. The factor names and levels are the same as those shown in Table 12.3 of Section 12.3. The generators for the design were $F = ABC$ and $G = ABD$. The data in Table 12.21 is in the data frame connector in the daewr package.
	- (a) What is the defining relation for this design, and how many of the 12 control-by-noise factor interactions can be estimated clear of other main effects or two-factor interactions?
- (b) Using the FrF2 package, can you find a 32-run resolution IV design that has more control-by-noise factor interactions clear? If so, what are the generators?
- (c) Using the data in Table 12.21, calculate a set of 31 saturated effects for this design, and make a normal plot to determine which effects, interactions, and confounded strings of two-factor interactions appear to be significant. Is there a clear interpretation of any confounded strings of interactions?
- (d) Make interaction and contour plots of any two-factor interactions between control factors and noise factors and use them to choose the level of control factors that will minimize the effect of noise factors.

(e) Are there any adjustment factors? If so, what levels should be chosen to maximize the pull-off force?

Table 12.21 Single-Array Experiment for Elastometric Connector A B C D E F G Pull-Off Force Low High High Low 120 150 75 22.0 High High High High 120 150 75 27.6 High High High Low 120 72 25 22.1 High High Low High 120 72 75 20.2 Low Low High 120 72 75 18.9 High High High High 24 150 25 13.8 Low High High High 24 72 75 15.2 Low Low Low Low 120 150 25 23.1 High Low High High 24 72 75 16.1 High Low High High 120 72 25 20.1 Low Low High High 120 150 75 21.9 High Low Low Low 24 72 25 17.1 High Low High Low 24 150 25 18.1 Low High Low High 24 150 75 9.6 Low Low High Low 24 72 75 18.3 Low High Low Low 120 72 75 19.1 High Low High Low 120 150 75 27.0 Low Low Low 24 150 75 17.3 Low Low High High 24 150 25 17.7 Low Low High 24 72 25 14.7 High Low Low Low 120 72 75 22.2 Low High High Low 24 150 25 21.1 Low Low High Low 120 72 25 24.3 Low High Low Low 24 72 25 13.9 High Low Low High 24 150 75 19.4 High Low Low High 120 150 25 22.7 High High Low High 24 72 25 14.6 High High Low Low 120 150 25 23.3 High High High Low 24 72 75 20.4 Low High Low High 120 150 25 22.6 Low High High High 120 72 25 21.0 High High Low Low 24 150 75 17.5

- 5. Reconsider the data from the injection molding experiment in Table 12.13.
	- (a) Fit the model $y = \beta_0 + \beta_A X_A + \beta_B X_B + \beta_{A \times B} X_A X_B$ in the adjustment factors using the method of least squares.
- (b) Simultaneously estimate the variance of the residuals at each level of the dispersion factor, C, and compute the weighted least squares estimates of the coefficients in the model in (a) using the lme functioon in the nlme package as shown in Section 12.6.1, page 543.
- 6. In the design of a thin film redistribution layer (cited by J. Lorenzen, IBM Kingston and discussed by Lawson and Madrigal (1994)), the circuit impedance (Z) is a function of three design factors: the A, insulator thickness; B , linewidth; and C , line height as shown in Figure 12.21. From engineering first principles, it can be shown that the impedance is given by Equation (12.10), where ϵ is the dielectric constant of the insulator and is assumed to be constant at 3.10.

$$
Z = f(A, B, C) = \frac{87.0}{\sqrt{\epsilon + 1.41}} \ln \left(\frac{5.98A}{0.8B + C} \right)
$$
(12.10)

The nominal or mean values of A, B , and C can be specified by the design engineer, but in actual circuits these characteristics will vary from their nominal values due to manufacturing imperfections and wear during use. The table below shows the feasible range and tolerance limits for these variables.

		$Low-Cost$
	Feasible	Tolerance
	Range	Range
Control Factor	(μm)	(μm)
A: Insulator thickness	$20 - 30$	± 1.0
B : Linewidth	12.5-17.5	± 0.67
$C:$ Line height	4-6	± 0.33

The goal is to find the nominal settings of A, B, and C that will result in $impedance = 85$, with minimum variance.

- (a) Construct a control-factor array in the design factors A, B, and C using a $2³$ factorial design with the ends of the feasible range as low and high values of the factors.
- (b) Construct a $3³$ noise-factor array (in deviations from the nominal settings in the control-factor array) using the 3 run table of Wang, Fang, and Lin (i.e., $nA < -c(c(.1667, .5, .8333))$ etc. Translate the levels in Table 12.16 into values in the low cost tolerance range of each factor using the formulas: $dA < -1*(nA-.5)/.5$, $dB < -0.667*((nB-.5)/.5)$, and $dC < -0.333 * ((nC - 0.5) / 0.5)$.
- (c) Create a product array of 216 rows by merging the noise factor array with each run or combination of factor levels in the control factor array.
- (d) Evaluate Equation (12.10) for each run or combination of levels in the product array, substituting for A, A+dA. Substituting for B,B+dB, and substituting for C, C+dC to simulate the impedance of an actual manufactured thin film redistribution layer.
- (e) Calculate the mean impedance and variance of impedance across the 27 runs in the noise array for each run or combination of factor levels in the control array. Include the mean impedance and log(variance) of impedence as new variables in the control array.
- (f) Determine which control factors have significant effects on the mean impedance and log(variance) of impedance.
- 7. Consider the data for the product array design for the elastometric connector shown in Figure 12.4 (the data is in the data frame prodstd in the daewr package).
	- (a) Calculate the mean pull-off force and log variance of the pull-off force across the noise array for each run in the control-factor array.
	- (b) Analyze the data using the location-dispersion modeling method.
	- (c) Do you find the same optimal levels of the control factors as identified in Section 12.4.2?
- (d) Is any information lost when analyzing this data using location-dispersion modeling?
- 8. An experiment originally performed by the National Railway Corporation of Japan (Taguchi and Wu, 1980) was reanalyzed by Box and Meyer (1986b). The control factors in the design were A, kind of welding rods; B, period of drying; C, welded materials; D, thickness; E, angle; F , opening; G , current; H , welding method; and J , preheating. Taguchi and Wu also considered the interactions AC , AG , AH , and GH . The design and response $y=$ tensile strength of welds is shown in Table 12.22 where e_1 and e_2 are unassigned columns that represent confounded interactions. The data is also in the data frame WeldS in the daewr package.
	- (a) Calculate effects for each of the 15 columns in Table 12.24, and make a normal plot to identify factors that affect the tensile strength.

EXERCISES 555

- (b) Fit a model to the data including only the effects that appear significant on the normal plot, and calculate the residuals from the fitted model.
- (c) Calculate the sample variance of residuals from the last model for the − and + level of each column in Table 12.24, and calculate the dispersion statistic (given by Equation (12.5)) for each column. Make a normal plot of the dispersion statistics and identify any potential dispersion effects.
- (d) Use the lme function in the nlme package to simultaneously estimate the location-dispersion effect using the method of iterative weighted least squares.
- (e) What factor levels do you recommend to maximize the tensile strength with minimum variation?